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NDS352AP

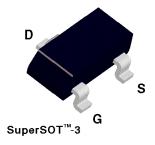
P-Channel Logic Level Enhancement Mode Field Effect Transistor

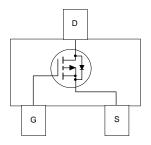
General Description

These P -Channel logic level enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance. These devices are particularly suited for low voltage applications such as notebook computer power management, portable electronics, and other battery powered circuits where fast high-side switching, and low in-line power loss are needed in a very small outline surface mount package.

Features

- = -0.9 A, -30 V. $R_{\rm DS(ON)}$ = 0.5 Ω @ $V_{\rm GS}$ = -4.5 V $R_{\rm DS(ON)}$ = 0.3 Ω @ $V_{\rm GS}$ = -10 V.
- Industry standard outline SOT-23 surface mount package using proprietary SuperSOTTM-3 design for superior thermal and electrical capabilities.
- High density cell design for extremely low R_{DS(ON)}.
- Exceptional on-resistance and maximum DC current capability.





Absolute Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter		NDS352AP	Units
V _{DSS}	Drain-Source Voltage		-30	V
V _{GSS}	Gate-Source Voltage - Continuous		±20	V
I _D	Maximum Drain Current - Continuous	(Note 1a)	±0.9	А
	- Pulsed		±10	
P_{D}	Maximum Power Dissipation	(Note 1a)	0.5	W
		(Note 1b)	0.46	
T_J , T_{STG}	Operating and Storage Temperature Range		-55 to 150	°C
THERMA	L CHARACTERISTICS			
R _{øJA}	Thermal Resistance, Junction-to-Ambient	(Note 1a)	250	°C/W
R _{øJC}	Thermal Resistance, Junction-to-Case	(Note 1)	75	°C/W

ymbol	Parameter	Conditions		Min	Тур	Max	Units
OFF CHA	RACTERISTICS						
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = -250 \mu\text{A}$		-30			V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = -24 V, V _{GS} = 0 V				-1	μA
			T _J =125°C			-10	μA
SSSF	Gate - Body Leakage, Forward	$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$				100	nA
GSSR	Gate - Body Leakage, Reverse	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
ON CHAR	ACTERISTICS (Note 2)						•
/ _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$		-0.8	-1.7	-2.5	V
,			T _J =125°C	-0.5	-1.4	-2.2	
R _{DS(ON)}	Static Drain-Source On-Resistance	$V_{GS} = -4.5 \text{ V}, I_{D} = -0.9 \text{ A}$			0.45	0.5	Ω
			T _J =125°C		0.65	0.7	
		$V_{GS} = -10 \text{ V}, I_{D} = -1 \text{ A}$			0.25	0.3	
O(ON)	On-State Drain Current	$V_{GS} = -4.5 \text{ V}, \ V_{DS} = -5 \text{ V}$		-2			Α
FS	Forward Transconductance	$V_{DS} = -5 \text{ V}, I_{D} = -0.9 \text{ A}$			1.9		S
YNAMIC	CHARACTERISTICS					•	•
iss	Input Capacitance	$V_{DS} = -15 \text{ V}, V_{GS} = 0 \text{ V},$ $f = 1.0 \text{ MHz}$			135		pF
oss	Output Capacitance				88		pF
rss	Reverse Transfer Capacitance				40		pF
WITCHIN	IG CHARACTERISTICS (Note 2)						
d(on)	Turn - On Delay Time	$V_{DD} = -6 \text{ V}, \ I_{D} = -1 \text{ A},$ $V_{GS} = -4.5 \text{ V}, \ R_{GEN} = 6 \Omega$			5	10	ns
	Turn - On Rise Time				17	30	ns
l(off)	Turn - Off Delay Time				35	70	ns
	Turn - Off Fall Time				30	60	ns
i(on)	Turn - On Delay Time	$V_{DD} = -10 \text{ V}, I_{D} = -1 \text{ A},$			8	15	ns
	Turn - On Rise Time	V_{GS} = -10 V, R_{GEN} = 50 Ω			16	30	ns
l(off)	Turn - Off Delay Time				35	90	ns
	Turn - Off Fall Time		_		30	90	ns
Q_g	Total Gate Charge	$V_{DS} = -10 \text{ V}, I_{D} = -0.9 \text{ A},$ $V_{GS} = -4.5 \text{ V}$			2	3	nC
Q_{gs}	Gate-Source Charge				0.5		nC
Q_{gd}	Gate-Drain Charge				1		nC

Electrical Characteristics (T _A = 25°C unless otherwise noted)							
Symbol	Parameter	Conditions	Min	Тур	Max	Units	
DRAIN-SOURCE DIODE CHARACTERISTICS AND MAXIMUM RATINGS							
I _s	Maximum Continuous Source Current				-0.42	Α	
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current				-10	Α	
V_{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, \ I_S = -0.42 \text{ (Note 2)}$		-0.8	-1.2	V	

Notes

1. R_{BJA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{BJC} is guaranteed by design while R_{BCA} is determined by the user's board design.

$$P_{D}(t) = \frac{T_{J} - T_{A}}{R_{\theta JA}(t)} = \frac{T_{J} - T_{A}}{R_{\theta JC} + R_{\theta CA}(t)} = I_{D}^{2}(t) \times R_{DS(ON)@T_{J}}$$

Typical $R_{_{\theta JA}}$ using the board layouts shown below on 4.5"x5" FR-4 PCB in a still air environment:

a. 250°C/W when mounted on a 0.02 in² pad of 2oz copper.

b. 270°C/W when mounted on a 0.001 in² pad of 2oz copper.





Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width \leq 300 μ s, Duty Cycle \leq 2.0%.

Typical Electrical Characteristics

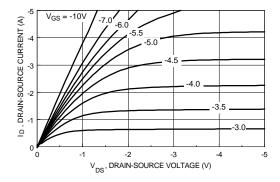


Figure 1. On-Region Characteristics.

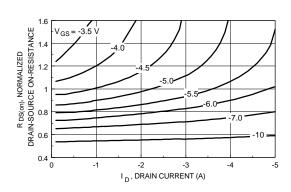


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

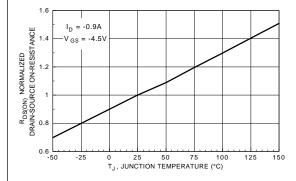


Figure 3. On-Resistance Variation with Temperature.

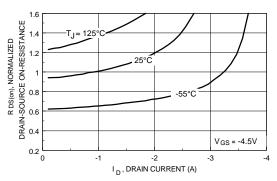


Figure 4. On-Resistance Variation with Drain Current and Temperature.

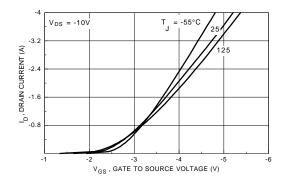


Figure 5. Transfer Characteristics.

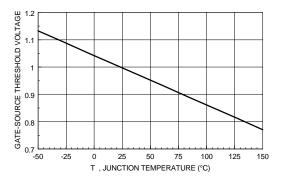


Figure 6. Gate Threshold Variation with Temperature.

Typical Electrical Characteristics (continued)

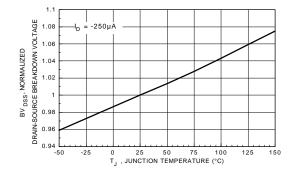


Figure 7. Breakdown Voltage Variation with Temperature.

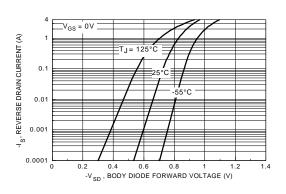


Figure 8. Body Diode Forward Voltage Variation with Source Current and Temperature.

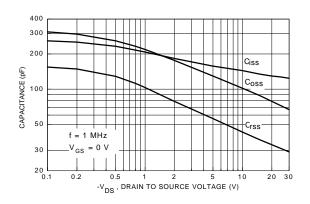


Figure 9. Capacitance Characteristics.

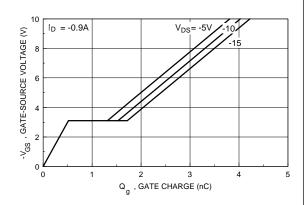


Figure 10. Gate Charge Characteristics.

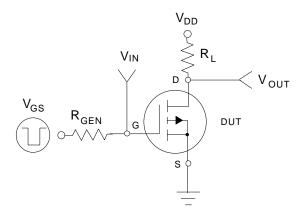


Figure 11. Switching Test Circuit.

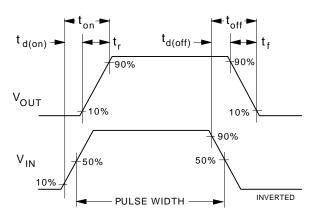


Figure 12. Switching Waveforms.

Typical Electrical Characteristics (continued)

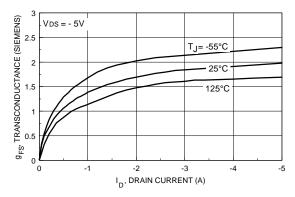


Figure 13. Transconductance Variation with Drain Current and Temperature.

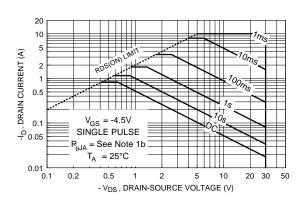
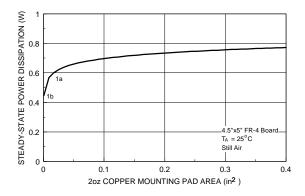


Figure 14. Maximum Safe Operating Area.



Figue 15. SuperSOT[™]-3 Maximum Steady-State Power Dissipation versus Copper Mounting Pad Area.

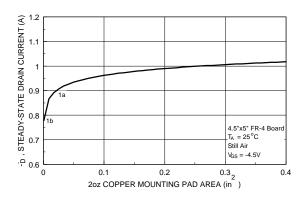


Figure 16. Maximum Steady-State Drain Current versus Copper Mounting Pad Area.

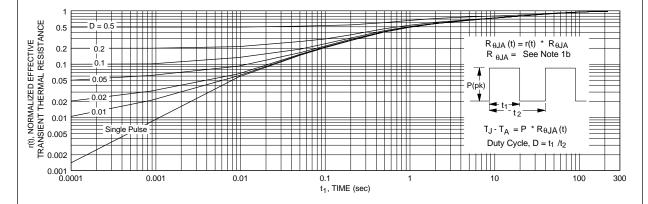


Figure 17. Transient Thermal Response Curve.

Note: Characterization performed using the conditions described in note 1b. Transient thermal response will change depending on the circuit board design.

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